

**Notice of References Cited**

Application/Control No.

09/771,354

Applicant(s)/Patent Under  
Reexamination  
MANGANINI ET AL.

Examiner

Arlen Soderquist

Art Unit

1743

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	H	US-			
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	J	US-			
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**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U	Mohd, A. A. et al, Analyst 1992, 117, 1743-1748.			
	V	Totland, M. M. et al, Chemical Geology 1995, 124, 21-36.			
	W	Wang, C.-F. et al, Analytica Chimica Acta 1996, 320, 207-216.			
	X	Wu, S. et al, Journal of Analytical Atomic Spectrometry 1996, 11, 287-296.			

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	5-305202	11-1993	JP	Ichinomiya et al.	
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Kingston, H. M. et al, Analytical Chemistry 1986, 58, 2534-2541.
	V	Matusiewicz, H. Journal of Analytical Atomic Spectrometry 1991, 6, 283-287.
	W	Karanassios, V. et al, Journal of Analytical Atomic Spectrometry 1991, 6, 457-463.
	X	Kojima, I. et al, Analytica Chimica Acta 1992, 264, 101-106.

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Zhi, Z.-L. et al, Critical Reviews in Analytical Chemistry 1996, 26, 239-260.
	V	Beary, E. S. et al, Analytical Chemistry 1997, 69, 758-766.
	W	Robbat, A., Jr. et al, Fresenius' Journal of Analytical Chemistry 1999, 364, 305-312.
	X	Hassler, D. R. et al, Chemical Geology 2000, 166, 1-14.

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.